What is claimed is:

1. A cantilever type probe card having probe needles disposed on the main body of the probe card, said probe needles being furnished respectively with bent parts having the leading terminals thereof directed toward an object under test and the parts including at least said bent parts having formed thereon reflection-lowering parts capable of repressing the reflection of light.

2. A cantilever type probe card according to claim 1, wherein said reflection-lowering parts are formed by the application of a delustering coat.

3. A cantilever type probe card according to claim 1, wherein said reflection-lowering parts are formed by the application of a delustering treatment by brushing.

4. A cantilever type probe card having probe needles disposed on the main body of the probe card, said probe needles being furnished respectively with bent parts having the leading terminals thereof directed toward an object under test and said bent parts being furnished with antireflection plates.

5. A method for the production of a cantilever type probe card having probe needles disposed on the main body of the probe card, which comprises a step for retaining horizontally the probe card having the probe needles disposed at prescribed positions and a step of immersing at least the bent parts of said probe needles in a coating material and forming a delustering coat on said bent parts.

6. A method according to claim 5, which further comprises a step of brushing at least said bent parts of said probe needles with a metallic brush thereby effecting a delustering treatment.

7. A method for the production of a cantilever type probe

card having probe needles disposed on the main body of the probe card, which comprises a step for attaching by adhesion to the main body of said probe card such antireflection plates as are adapted to cover said bent parts of said probe needles and provided with openings for exposing the tips of said probe needles.